TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE

S S M 3 K 0 1 F

HIGH SPEED SWITCHING APPLICATIONS

Small Package

Low on Resistance : Ron = $120 \text{ m}\Omega$ (Max) (VGS = 4 V)

: Ron = 150 m Ω (Max) (VGS = 2.5 V)

Low Gate Threshold Voltage: $Vth = 0.6 \sim 1.1 \text{ V}$

 $(V_{DS} = 3 V, I_{D} = 0.1 mA)$

MAXIMUM RATINGS (Ta = 25°C)

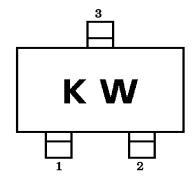
| CHARACTERISTIC | | SYMBOL | RATING | UNIT | |
|---------------------------|----------|------------------|---------|------|--|
| Drain-Source Voltage | v_{DS} | 30 | V | | |
| Gate-Source Voltage | | v_{GSS} | ±10 | V | |
| Drain Current | DC | $I_{\mathbf{D}}$ | 1.3 | A | |
| | Pulse | I_{DP} | 2.6 | | |
| Drain Power Dissipation | | $P_{\mathbf{D}}$ | 200 | mW | |
| Channel Temperature | | T_{ch} | 150 | °C | |
| Storage Temperature Range | | $T_{ m stg}$ | -55~150 | °C | |

GATE SOURCE 3. DRAIN S-MINI **JEDEC** TO-236MOD EIAJ SC-59 TOSHIBA 2-3F1F

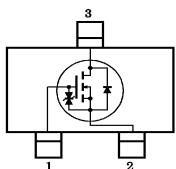
Unit in mm

Weight: 0.012 g

MARKING



EQUIVALENT CIRCUIT



HANDLING PRECAUTION

When handling individual devices (which are not yet mounted on a circuit board), be sure that the environment is protected against electrostatic electricity. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.

TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.

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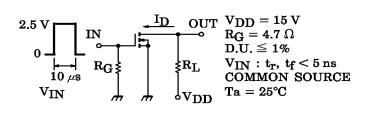
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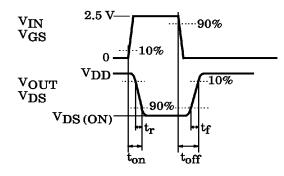
ELECTRICAL CHARACTERISTICS (Ta = 25°C)

| CHARAC | CTERISTIC | SYMBOL | TEST CONDITION | | TYP. | MAX. | UNIT |
|------------------------------------|---|---|---|-----|-----------|------------|--------------------|
| Gate Leakage | e Current I_{GSS} $V_{GS} = \pm 10 \text{ V}, V_{DS} = 0$ | | _ | | ±5 | μ A | |
| Drain-Source Breakdown Voltage | | V (BR) DSS | $I_D = 1 \text{ mA}, V_{GS} = 0$ | 30 | _ | _ | v |
| Drain Cut-off | Current | $I_{ m DSS}$ | $V_{DS} = 30 \text{ V}, \ V_{GS} = 0$ | _ | _ | 1 | μ A |
| Gate Thresho | ld Voltage | $ m v_{th}$ | $V_{ m DS} = 3 m V, I_{ m D} = 0.1 mA$ | 0.6 | _ | 1.1 | V |
| Forward Tran Admittance | nsfer | Y _{fs} | $V_{DS} = 3 V, I_{D} = 0.65 A$ (Note 1) | 2.0 | _ | _ | s |
| Drain-Source ON Resistance | | R _{DS} (ON) | $I_D = 0.65 \text{ A}, V_{GS} = 4V$ (Note 1) $I_D = 0.65 \text{ A}, V_{GS} = 2.5 \text{ V}$ (Note 1) | | 85 115 | 120 150 | $\mathbf{m}\Omega$ |
| Input Capacit | tance | C_{iss} | $V_{DS} = 10 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$ | _ | 152 | _ | рF |
| Reverse Transfer Capacitance Crss | | ${ m V_{DS}} = 10 \ { m V}, \ { m V_{GS}} = 0, \ { m f} = 1 \ { m MHz}$ | _ | 41 | _ | pF | |
| Output Capacitance Coss | | $V_{DS} = 10 \text{ V}, \ V_{GS} = 0, \ f = 1 \text{ MHz}$ | _ | 102 | _ | рF | |
| Switching | Turn-on Time | ton | $V_{DD} = 15 \text{ V}, I_D = 0.5 \text{ A},$ | _ | 45 | _ | na |
| Time | Turn-off Time | $t_{ m off}$ | $V_{GS} = 0 \sim 2.5 \text{ V}, R_G = 4.7 \Omega$ | _ | 69 | _ | ns |

(Note 1): Pulse test

SWITCHING TIME TEST CIRCUIT





PRECAUTION

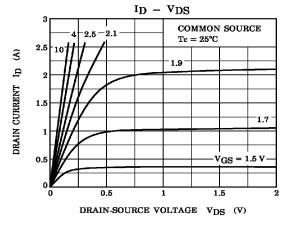
 V_{th} can be expressed as voltage between gate and source when low operating current value is $I_D=100~\mu A$ for this product. For normal switching operation, $V_{GS\,(ON)}$ requires higher voltage than V_{th} and $V_{GS\,(off)}$ requires lower voltage than V_{th} .

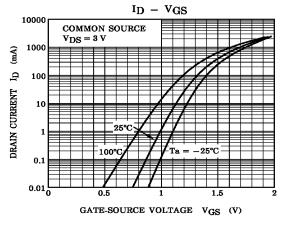
(Relationship can be established as follows : $V_{GS (off)} < V_{th} < V_{GS (ON)}$)

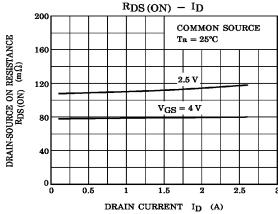
Please take this into consideration for using the device.

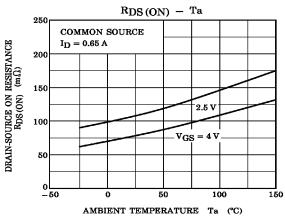
VGS recommended voltage of 2.5 V or higher to turn on this product.

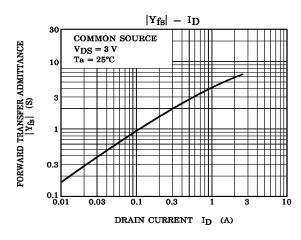
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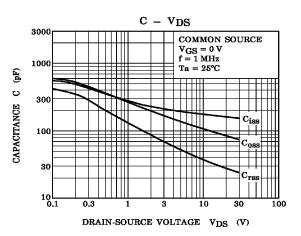




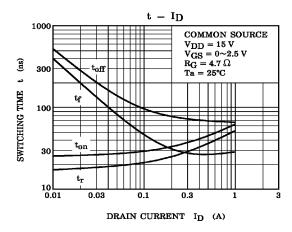


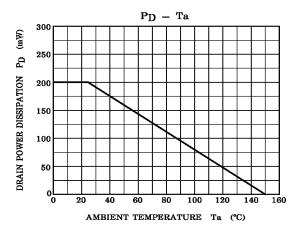


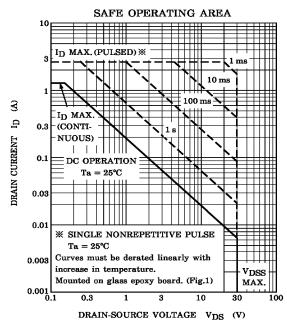




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(Fig.1): $25.4 \,\mathrm{mm} \times 25.4 \,\mathrm{mm} \times 1.6 \,\mathrm{t}$ (a Cu pad of $0.8 \,\mathrm{mm}^2$ area)



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